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# Six-Port Reflectometer in WR15 Metallic Waveguide for Free-Space Sensing Applications

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Abstract — This work describes the design, fabrication and measurements of a six-port reflectometer in metallic waveguide technology for operation around 60 GHz. The system integration is based on WR15 building blocks. An insitu linearization of the detectors associated to a vector calibration procedure is provided to determine the calibrated IQ components from the measured voltages. Near-field free-space distance measurements from contact to stand-off distance of two free-space wavelengths are shown to validate the technique proposed.

Index Terms — Six-port, reflectometer, IQ demodulation, millimeter-wave, distance measurement,

#### I. INTRODUCTION

The six-port technique has been introduced in the 1970s as a simple technique for measuring power and reflection coefficient in the microwave regime [1]. Since then, a variety of six-port systems have been exemplary demonstrated in metallic guide, substrate integrated waveguide (SIW), planar and monolithic forms [2]-[8]. Each technology presents own advantages and drawbacks in terms of circuit size, power consumption, immunity to temperature/hygrometry variations, fabrication facility, system integration, measurement performance and cost [8]. Therefore, the choice of the technology is mainly driven by the requirements of the targeted application.

This work presents a fully WR15 metallic waveguide six-port reflectometer operating at 60 GHz for near-field sensing applications, i.e. near-field high precision distance measurement. Unlike planar technologies systems, waveguides are highly shielded to provide isolation between nearby signals. As they rely on air as a dielectric, the technology reduces the need for consistency in the dielectric material and presents better immunity to environmental variations. Furthermore, the building blocks of the six-port circuit can be easily connected each other as they are inherently matched. As the size is directly related to the operation wavelength, millimeterwave frequency operation is preferred to reduce the circuit size.

#### II. SIX-PORT IO DEMODULATOR

This section describes the design, fabrication and test of the six-port IQ demodulator. The proposed architecture and picture of the fabricated system are given in Fig. 1.

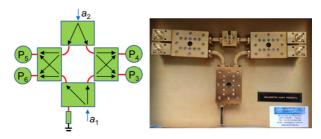


Fig. 1. (a) Structure of the six-port IQ demodulator. (b) Photograph of the WR15 waveguide six-port IQ demodulator.

The circuit is implemented using three 90° hybrids with 20 dB isolation and 6 % bandwidth around 60 GHz, a four port hybrid tee with one arm connected to a match termination for basic power splitting and four power detectors with typical video sensitivity of 500 mV/mW and tangential sensitivity of -50 dBm. Interconnecting bends and twists are used for system integration. The reference millimeter-wave signal  $a_1$  [fig. 1(a)] can be provided by a miniature high stability phase-locked source Mi-WAVE<sup>TM</sup> 957 ( $P_{LO}=11$  dBm) or a frequency synthetizer Keysight<sup>TM</sup> E8257D.

The first step concerns the linearization of the electrical response of the power detectors to correct deviation from quadratic response. For this experiment, the RF port (signal  $a_2$ ) of the six-port demodulator is connected to a match termination to make the electrical response depending only of the LO source signal  $a_1$ . We present in Fig. 2 the detected voltages  $V_1$  to  $V_4$  measured for a source power varying from 10  $\mu$ W to 10 mW at 60 GHz.

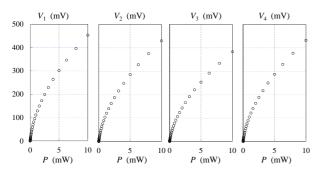


Fig. 2. Detected voltages as a function of the input millimeter-wave LO power – F = 60 GHz.

From Fig. 2, the linearity is degraded by distorsions. The linearization procedure consists to interpolate the measured data using a polynomial function. In this study, a  $5^{th}$  order polynomial is used. As an example, the interpolation model for the voltage  $V_1$  is given by

$$P_1$$
 (mW) = -1.43×10<sup>-13</sup>  $V_1^5$  + 1.66×10<sup>-10</sup>  $V_1^4$  - 8.04×10<sup>-8</sup>  $V_1^3$  + 5.98×10<sup>-5</sup>  $V_1^2$  + 4.02×10<sup>-3</sup>  $V_1$  + 1.36×10<sup>-2</sup>.

The next step consists of verifying the performance in mixing mode. In this configuration, the millimeter-wave signal  $a_2$  with amplitude  $A_{RF}$  is combined with the signal  $a_1$  with amplitude  $A_{LO}$ . The theoretical powers  $P_3$  to  $P_6$  are given by

$$P_3 = |0.5(a_2 + a_1)|^2 \tag{1}$$

$$P_4 = |0.5(a_2 - ja_1)|^2 \tag{2}$$

$$P_5 = |0.5(a_2 - a_1)|^2 \tag{3}$$

$$P_6 = |0.5(a_2 + ja_1)|^2 \tag{4}$$

The 60 GHz LO and RF input signals are both obtained by the synthesizer using a power splitter. The source power is set to 11 dBm. The RF signal amplitude  $A_{\rm RF}$  and relative phase-shift  $\Delta\Phi$  are respectively adjusted with precise WR15 waveguide variable attenuator (MI-WAVE 510V/385) and phase-shifter (MI-WAVE 528V/385) as shown in Fig. 3. The IQ components are defined as

$$I = A_{\rm RF} \cos(\Delta \Phi) \sim P_3 - P_5 \tag{5}$$

$$Q = A_{\rm RF} \sin(\Delta \Phi) \sim P_6 - P_4 \tag{6}$$

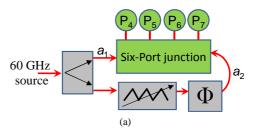
A spatial (related to the spatial phase-shift  $\Delta\Phi$ ) Fourier analysis is considered to correct the general forms given by (5) and (6) into the models (7) and (8) that encompasses mismatching and non-linear effects [9].

$$P_3 - P_5 = y_0 + y_1 I + y_2 Q + y_3 I^2 + y_4 Q^2 + y_5 (I^2 - 3IQ^2) + y_5 (Q^2 - 3I^2 Q)$$
 (7)

$$P_6 - P_4 = y_0' + y_1'I + y_2'Q + y_3'I^2 + y_4'Q^2 + y_5'(I^2 - 3IQ^2) + y_6'(Q^2 - 3I^2Q)$$
(8)

These equations rely the powers to polynomial combinations of I and Q through eight real calibration

constants  $y_i$  and  $y'_i$ . More information about the model construction is given in [9].



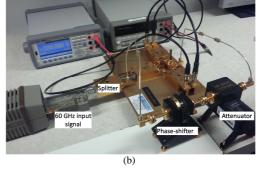


Fig. 3. Experimental test bench arrangement for IQ measurements.

The calibration coefficients  $y_i$  and  $y_i'$  are determined by fitting the measured powers to the models (7) and (8). For comparison purposes, the calibration constants are determined for the 1<sup>st</sup> ( $y_3 = y_4$  and  $y_5 = y_6 = y_7 = 0$ ), the 2<sup>nd</sup> ( $y_6 = y_7 = 0$ ) and the 3<sup>rd</sup> orders. Table I reports the parameters obtained for  $P_3 - P_5$ . The 3D fitting according to the 3<sup>rd</sup> order model is also illustrated in Fig. 4. These results show that the spatial non-linearity effect has relatively low impact. However, metrological applications that require a high degree of accuracy can benefit from a 3<sup>rd</sup> order model that achieves a determination coefficient of nearly 1 computed on 259 points. Equivalent result has been found for  $P_6 - P_4$ . The calibration has been also validated in the frequency band 55-75 GHz.

TABLE I. Calibration coefficients established for  $P_3 - P_5 \text{-} \text{F=} 60 \text{ GHz}.$ 

Coefficient	Parameter	Order 1	Order 2	Order 3
$Y_0$	1	-0.2457	-0.2457	-0.2457
<i>y</i> 1	I	0.6575	0.6592	0.6593
y 2	Q	-1.1466	-1.1466	-1.1466
у 3	$\mathbf{I}^2$	-0.0102	-0.0504	-0.0504
<i>y</i> <sub>4</sub>	$Q^2$		0.0321	0.0321
<i>y</i> <sub>5</sub>	IQ		-0.0152	-0.0152
у6	$I^{3}$ -3 I $Q^{2}$		_	-0.0001
<i>y</i> <sub>7</sub>	$Q^3$ -3 $I^2$ $Q$			-0.0128
r <sup>2</sup>		99.80%	99.88%	99.89%

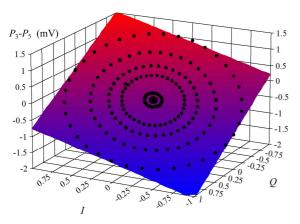
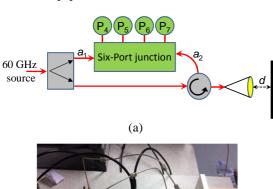
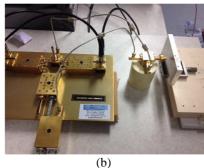


Fig. 4. IQ demodulation at 60 GHz: 3D complex interpolation – F=60 GHz. (  $\bullet$  Measured data ).

#### II. DISTANCE SENSING APPLICATIONS

A distance measurement sensor based on the six-port demodulator associated to WR15 power divider, circulator and horn antenna is given in Fig. 5. The antenna with vertical polarization has been tested with stand-off d from contact to 10 mm to a metallic target. For example, detected voltage  $V_1$  as a function of d shows the spread propagation losses that increase with d. Furthermore, resonances are related to wave recombination between the reflected wave by that target, the guided reflected wave at the antenna input (mismatch) and the free-space source match term (reflection of the received wave by the antenna). A dedicated free-space calibration method that takes into account these two effects can be implemented to derive the distance as a function of the measured voltages [10]. Complementary results will be shown in the last version of the paper.





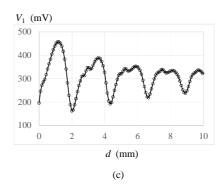


Fig. 5. Free-space distance measurement – F = 60 GHz. (a) and (b) Experimental test bench. (c) Detected voltage  $V_1$  as a function of the stand-off d.

#### V. CONCLUSION

A 60 GHz six-port IQ demodulator in WR15 guide technology has been designed and tested. On this basis, a free-space six-port reflectometer has been described for close distance measurement in the cm range. Preliminary experiments show propagation of spherical waves combined with free-space stationary waves. Future work will provide all necessary calibration procedure for accurate extraction of distance and precision analysis.

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